PCN Number: 20140709002A **PCN Date:** 10/17/2014 Qualification of TI Chengdu (CDAT) as Additional Assembly and Test Site for Select Title: X2QFN/X2SON Package Devices **PCN** Manager **Phone:** +1(214)480-6037 **Customer Contact: Dept:** Quality Services **Change Type:** Assembly Site Design Wafer Bump Site **Assembly Process** Data Sheet Wafer Bump Material **Assembly Materials** Part number change Wafer Bump Process Mechanical Specification Wafer Fab Site Test Site Test Process Packing/Shipping/Labeling Wafer Fab Materials Wafer Fab Process

PCN Details

Description of Change:

Revision A is to remove select devices in the Product Affected Section (with strikethrough) and highlighted in yellow. These devices were inadvertently added and not affected by this change.

Texas Instruments Incorporated is announcing the qualification of TI Chengdu (CDAT) as Additional Assembly and Test Site for select devices listed in the "Product Affected" Section. Current assembly sites are as follows and material differences as follows.

	From	То
Assembly/Test Sites	JCETCZ, HNT, NSE	CDAT

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Reason for Change:

Continuity of supply.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

Changes to product identification resulting from this PCN:

Assembly Site		
JCETCZ	Assembly Site Origin (22L)	ASO: GP6
HNT	Assembly Site Origin (22L)	ASO: HNT
NSE	Assembly Site Origin (22L)	ASO: NSE
TI Chengdu (CDAT)	Assembly Site Origin (22L)	ASO: CDA

ASSEMBLY SITE CODES: JCETCZ = F, HNT = H, NSE = J, CDAT = 8

Sample product shipping label (not actual product label)





(1P) SN74LS07NSR (P) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2 (2P) REV: 0033317 (2P) REV: (V) 0033317 (20L) CSO:SHE (21L) CCO:USA (22L) ASO:MLA (23L) ACO:MYS

Product Affected:			
SN1205066PDQNR	SN74LVC1G08DSFR	TLV707285PDQNR	TPL0102-100RUCR
SN1206013PDQNR	SN74LVC1G11DSFR	TLV70732DQNR	TPS3839G18DQNR
SN74AUP1G02DSFR	SN74LVC1G66DSFR	TLV70736PDQNR	TPS3839G33DQNR
SN74AUP1G126DSFR	SN74LVC2G07DSFR	TLV71320DQNR	TPS3839K33DQNR
SN74AUP1G14DSFR	TLV70712PDQNR	TLV717185PDQNR	TPS3839K50DQNR
SN74AUP1G32DSFR	TLV70718PDQNR	TLV71718PDQNR	TPS3839L30DQNR
SN74AUP2G07DSFR	TLV70719PDQNR	TLV71727PDQNR	
SN74LVC1G02DSFR	TLV70725PDQNR	TLV71729PDQNR	
SN74LVC1G07DSFR	TLV707285DQNR	TLV71733PDQNR	

Qualification Report Chengdu A/T startup X2QFN/X2SON Product Attributes

	Qual Device: SN74LVC1G04DSFR	Qual Device: TLV70728PDQNR	Qual Device: TPL0102-100RUCR
Die Attributes			
Die Revision	G	В	A
Wafer Fab Supplier	CFAB	FFAB	MH8
Wafer Fab Process	ASLC10	LBC7	LBC7T
Package Attributes			
Assembly Site	CHENGDU	CHENGDU	CHENGDU
Package Family	X2SON	X2SON	X2QFN
Package Designator	DSF	DQN	RUC
Package Size (mils)	39.37 X 39.37	39.37 X 39.37	78.74 X 78.74
Body Thickness (mils)	15.75	15.75	15.75
Pin Count	Count 6		14
Lead Frame Type	Cu	Cu	Cu
Lead Finish	NiPdAu	NiPdAu	NiPdAu
Lead Pitch (mils)	13.78	25.59	15.75
Mount Compound	4221460	4221460	4221460
Mold Compound	4210087	4210087	4210087
Bond Wire Composition	Au	Au	Au
Bond Wire Diameter (mils)	0.8	0.8	0.8
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0

⁻ QBS: Qual By Similarity - Qual Devices qualified at LEVEL1-260C: SN74LVC1G04DSFR, TLV70728PDQNR, TPL0102-100RUCR

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: SN74LVC1G04DSFR	Qual Device: TLV70728PDQNR	Qual Device: TPL0102- 100RUCR
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0	3/229/0	3/231/0
ТС	Temperature Cycle, - 65/+150C	500 Cycles	3/231/0	3/231/0	4/308/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	3/231/0
HTOL	Life Test, 150C	300 Hours	3/231/0	-	1/77/0
WBS	Bond Shear	Wires	3/228/0	3/228/0	3/228/0
WBP	Bond Pull	Wires	3/228/0	3/228/0	3/228/0
SD	Solderability	Pb-Free	-	3/66/0	3/66/0
PD	Physical Dimensions		3/15/0	3/15/0	3/15/0
HBM	ESD - HBM	500 V	-	3/9/0	-
CDM	ESD - CDM	250 V	-	3/9/0	-
	Backgrind Characterization		Pass	Pass	Pass
ED	Electrical Characterization, side by side	-	Pass	Pass	Pass
FLAM	Flammability	UL 94V-0	-	-	3/15/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass
MSL	Moisture Sensitivity Level	Level 1@260C	3/36/0	3/35/0	3/36/0
	Salt Atmosphere	24 Hours	-	3/66/0	3/66/0
YLD	FTY and Bin Summary	-	Pass	Pass	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV:150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

TI Qualification ID: 20131112-97501

N/A = Not Applicable

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com